

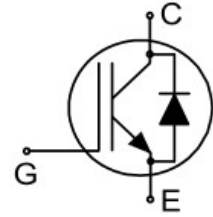
# HC50N75

50A/750V

Trench FS IGBT

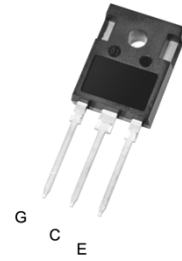
### Features and Benefits:

- Plug and play replacement of previous generation IGBTs
- 750V breakdown voltage
- Low gate charge  $Q_G$
- Maximum junction temperature 175°C
- Qualified according to JEDEC for target applications
- Pb-free lead plating; RoHS compliant



### Applications:

- Uninterruptible power supplies
- Solar converters
- Welding converters
- Mid to high range switching frequency converters



### Package pin definition:

- Pin 1 - gate
- Pin 2 & backside - collector
- Pin 3 – emitter

### Key Performance and Package Parameters

Type	$V_{CE}$	$I_c$	$V_{CEsat}, T_{vj}=25^{\circ}C$	$T_{vjmax}$	Marking	Package
HC50N75	750V	50A	1.89V	175°C	HC50N75	TO-247

**Absolute maximum ratings**

Parameter	Symbol	Value	Unit
Collector-emitter voltage, $T_{vj} \geq 25^{\circ}\text{C}$	$V_{CE}$	750	V
DC collector current, limited by $T_{vjmax}$ $T_C = 25^{\circ}\text{C}$ value limited by bondwire $T_C = 100^{\circ}\text{C}$	$I_C$	80 50	A
Pulsed collector current, $t_p$ limited by $T_{vjmax}$ <sup>1)</sup>	$I_{Cpuls}$	200	A
Turn off safe operating area $V_{CE} \leq 650\text{V}$ , $T_{vj} \leq 175^{\circ}\text{C}$ , $t_p = 1\mu\text{s}$ <sup>1)</sup>	-	200	A
Diode forward current, limited by $T_{vjmax}$ $T_C = 25^{\circ}\text{C}$ value limited by bondwire $T_C = 100^{\circ}\text{C}$	$I_F$	80 50	A
Diode pulsed current, $t_p$ limited by $T_{vjmax}$ <sup>1)</sup>	$I_{Fpuls}$	200	A
Power dissipation $T_C = 25^{\circ}\text{C}$ Power dissipation $T_C = 100^{\circ}\text{C}$	$V_{GE} \leq 10\mu\text{s}, D < 0.010$	$\pm 20$ V	W
	$P_{tot}$	$\pm 30$ 294 147	
Operating junction temperature	$T_{vj}$	-40...+175	$^{\circ}\text{C}$
Storage temperature	$T_{stg}$	-55...+150	$^{\circ}\text{C}$
Soldering temperature, wave soldering 1.6mm (0.063in.) from case for 10s		270	$^{\circ}\text{C}$
Mounting torque, M3 screw, PG-TO247-pin123 Maximum of mounting processes: 3	M	0.6	Nm

**Thermal Resistance**

Parameter	Symbol	Conditions	Value			Unit
			min.	typ.	max.	

**R<sub>th</sub> Characteristics**

IGBT thermal resistance, junction - case	$R_{th(j-c)}$		-	0.51	-	$^{\circ}\text{C/W}$
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Diode thermal resistance, junction - case	$R_{th(j-c)}$	-	0.71	-	°C/W
Thermal resistance junction - ambient	$R_{th(j-a)}$	-	31	-	°C/W

<sup>1)</sup> Defined by design. Not subject to production test.

**Electrical Characteristic, at  $T_{vj} = 25^{\circ}\text{C}$ , unless otherwise specified**

Parameter	Symbol	Conditions	Value			Unit
			min.	typ.	max.	
<b>Static Characteristic</b>						
Collector-emitter breakdown voltage	$V_{(BR)CES}$	$V_{GE}=0V, I_C=0.2mA$	750	-	-	V
Collector-emitter saturation voltage	$V_{CEsat}$	$V_{GE}=15V, I_C=50A$	-	1.89	2.10	V
		$T_{vj}=25^{\circ}\text{C}$	-	2.37	-	
		$T_{vj}=175^{\circ}\text{C}$	-	2.65	-	
Diode forward voltage	$V_F$	$V_{GE}=0V, I_F=50.0A$	-	2.46	1.70	V
		$T_{vj}=25^{\circ}\text{C}$	-	2.27	-	
		$T_{vj}=175^{\circ}\text{C}$	-	2.14	-	
Gate-emitter threshold voltage	$V_{GE(th)}$	$I_C=0.5mA, V_{CE}=V_{GE}$	5.5	6.1	6.5	V
Zero gate voltage collector current	$I_{CES}$	$V_{CE}=650V, V_{GE}=0V$	-	0.022	50	$\mu\text{A}$
		$T_{vj}=25^{\circ}\text{C}$	-	278	-	
Gate-emitter leakage current	$I_{GES}$	$V_{CE}=0V, V_{GE}=20V$	-	-	100	nA
Transconductance	$g_{fs}$	$V_{CE}=20V, I_C=50A$	-	21.2	-	S

**Electrical Characteristic, at  $T_{vj} = 25^{\circ}\text{C}$ , unless otherwise specified**

Parameter	Symbol	Conditions	Value			Unit
			min.	typ.	max.	
<b>Dynamic Characteristic</b>						
Input capacitance	$C_{ies}$	$V_{CE}=25V, V_{GE}=0V, f=1\text{MHz}$	-	2509	-	$\mu\text{F}$
Output capacitance	$C_{oes}$		-	165	-	
Reverse transfer capacitance	$C_{res}$		-	28	-	
Gate charge	$Q_G$	$V_{CC}=520V, I_C=40A, V_{GE}=15V$	-	100.4	-	nC

**Switching Characteristic, Inductive Load**

Parameter	Symbol	Conditions	Value			Unit
			min.	typ.	max.	
<b>Dynamic Characteristic</b>						
Turn-on delay time	$t_{d(on)}$	$T_{vj}=25^{\circ}C,$ $V_{CC}=400V, I_C=50A,$ $V_{GE}=0.0/15.0V,$ $R_{G(on)}=12.0\Omega, R_{G(off)}=12.0\Omega$	-	33	-	ns
Rise time	$t_r$		-	141	-	ns
Turn-off delay time	$t_{d(off)}$		-	138	-	ns
Fall time	$t_f$		-	65	-	ns
Turn-on energy	$E_{on}$		-	3.2	-	mJ
Turn-off energy	$E_{off}$		-	1.1	-	mJ
Total switching energy	$E_{ts}$	-	4.3	-	mJ	
Turn-on delay time	$t_{d(on)}$	$T_{vj}=25^{\circ}C,$ $V_{CC}=400V, I_C=25A,$ $V_{GE}=0.0/15.0V,$ $R_{G(on)}=12.0\Omega, R_{G(off)}=12.0\Omega,$	-	25	-	ns
Rise time	$t_r$		-	61	-	ns
Turn-off delay time	$t_{d(off)}$		-	155	-	ns
Fall time	$t_f$		-	53	-	ns
Turn-on energy	$E_{on}$		-	1.1	-	mJ
Turn-off energy	$E_{off}$		-	0.5	-	mJ
Total switching energy	$E_{ts}$	-	1.6	-	mJ	

**Diode Characteristic, at  $T_{vj}=25^{\circ}C$** 

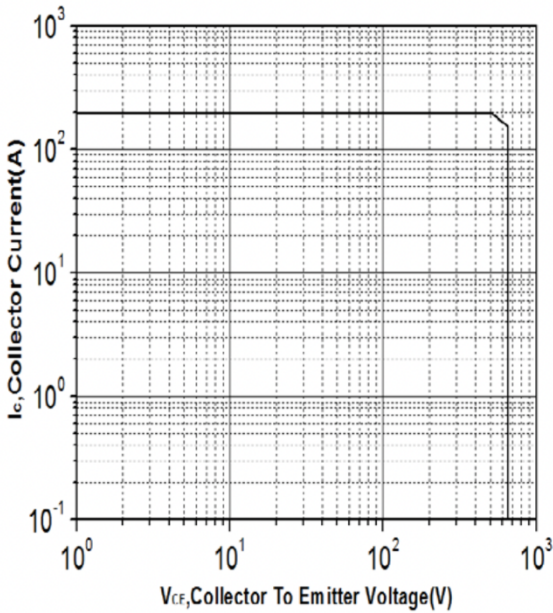
Parameter	Symbol	Conditions	Value			Unit
			min.	typ.	max.	
<b>Dynamic Characteristic</b>						
Diode reverse recovery time	$t_{rr}$	$T_{vj}=25^{\circ}C,$ $V_R=400V,$ $I_F=50A,$ $di_F/dt=500A/\mu s$	-	182	-	ns
Diode reverse recovery charge	$Q_{rr}$		-	1.35	-	$\mu C$
Diode peak reverse recovery current	$I_{rrm}$		-	17	-	A
Diode reverse recovery time	$t_{rr}$	$T_{vj}=25^{\circ}C,$ $V_R=400V,$ $I_F=25A,$ $di_F/dt=500A/\mu s$	-	167	-	ns
Diode reverse recovery charge	$Q_{rr}$		-	1.02	-	$\mu C$
Diode peak reverse recovery current	$I_{rrm}$		-	15	-	A

### Switching Characteristic, Inductive Load

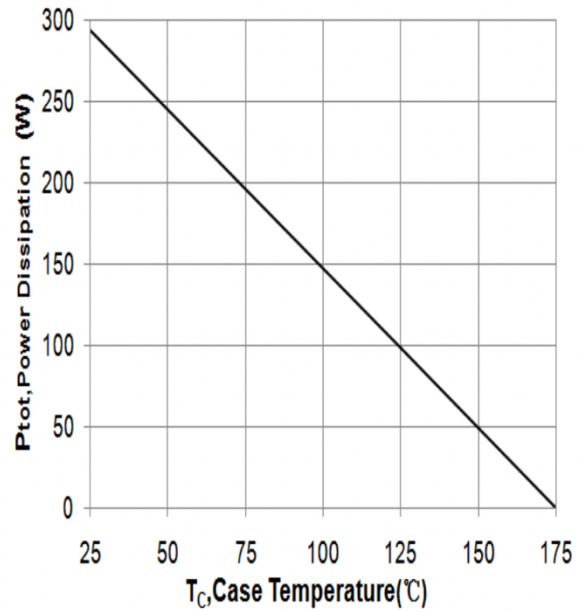
Parameter	Symbol	Conditions	Value			Unit
			min.	typ.	max.	
<b>IGBT Characteristic, at <math>T_{vj}=150^{\circ}\text{C}</math></b>						
Turn-on delay time	$t_{d(on)}$	$T_{vj}=150^{\circ}\text{C},$ $V_{CC}=400\text{V}, I_C=50\text{A},$ $V_{GE}=0.0/15.0\text{V},$ $R_{G(on)}=12.0\Omega, R_{G(off)}=12.0\Omega$	-	33	-	ns
Rise time	$t_r$		-	158	-	ns
Turn-off delay time	$t_{d(off)}$		-	158	-	ns
Fall time	$t_f$		-	108	-	ns
Turn-on energy	$E_{on}$		-	3.9	-	mJ
Turn-off energy	$E_{off}$		-	1.5	-	mJ
Total switching energy	$E_{ts}$		-	5.4	-	mJ
Turn-on delay time	$t_{d(on)}$	$T_{vj}=150^{\circ}\text{C},$ $V_{CC}=400\text{V}, I_C=25\text{A},$ $V_{GE}=0.0/15.0\text{V},$ $R_{G(on)}=12.0\Omega, R_{G(off)}=12.0\Omega$	-	24	-	ns
Rise time	$t_r$		-	62	-	ns
Turn-off delay time	$t_{d(off)}$		-	208	-	ns
Fall time	$t_f$		-	90	-	ns
Turn-on energy	$E_{on}$		-	1.1	-	mJ
Turn-off energy	$E_{off}$		-	0.8	-	mJ
Total switching energy	$E_{ts}$		-	1.9	-	mJ

### Diode Characteristic, at $T_{vj}=150^{\circ}\text{C}$

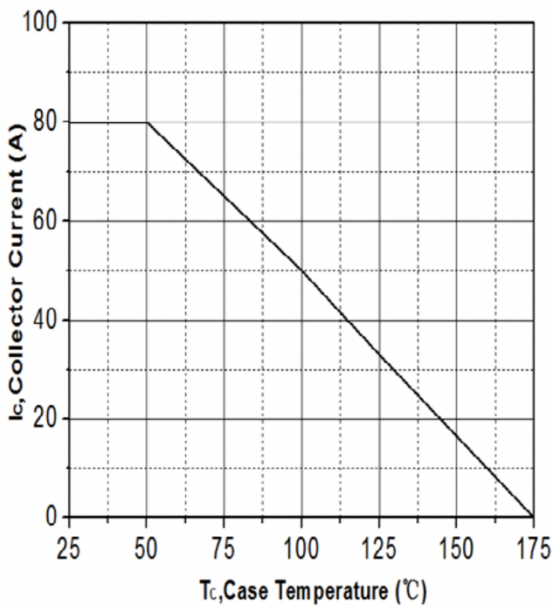
Parameter	Symbol	Conditions	Value			Unit
			min.	typ.	max.	
<b>Dynamic Characteristic</b>						
Diode reverse recovery time	$t_{rr}$	$T_{vj}=150^{\circ}\text{C},$ $V_R=400\text{V},$ $I_F=50\text{A},$ $di_F/dt=500\text{A}/\mu\text{s}$	-	225	-	ns
Diode reverse recovery charge	$Q_{rr}$		-	4.5	-	$\mu\text{C}$
Diode peak reverse recovery current	$I_{rrm}$		-	37.7	-	A
Diode reverse recovery time	$t_{rr}$	$T_{vj}=150^{\circ}\text{C},$ $V_R=400\text{V},$ $I_F=25\text{A},$ $di_F/dt=500\text{A}/\mu\text{s}$	-	207	-	ns
Diode reverse recovery charge	$Q_{rr}$		-	3.3	-	$\mu\text{C}$
Diode peak reverse recovery current	$I_{rrm}$		-	30.6	-	A



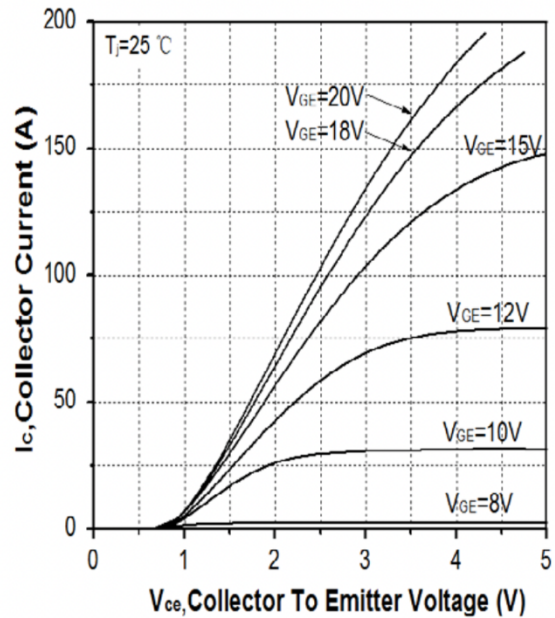
**Figure 1. Forward bias safe operating area**  
( $D=0, T_C=25^\circ\text{C}, T_J \leq 175^\circ\text{C}, V_{GE}=15\text{V}, t_p=1\mu\text{s}$ ,  
 $I_{Cmax}$  defined by design – not subject to production test)



**Figure 2. Power dissipation as a function of case temperature**  
( $T_J \leq 175^\circ\text{C}$ )



**Figure 3. Collector current as a function of case temperature**  
( $V_{GE} \geq 15\text{V}, T_J \leq 175^\circ\text{C}$ )



**Figure 4. Typical output characteristic**  
( $T_J = 25^\circ\text{C}$ )

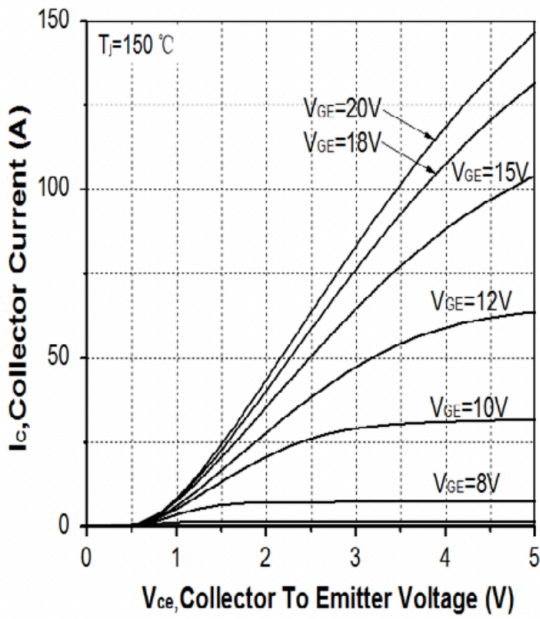


Figure 5. Typical output characteristic ( $T_j = 150^\circ\text{C}$ )

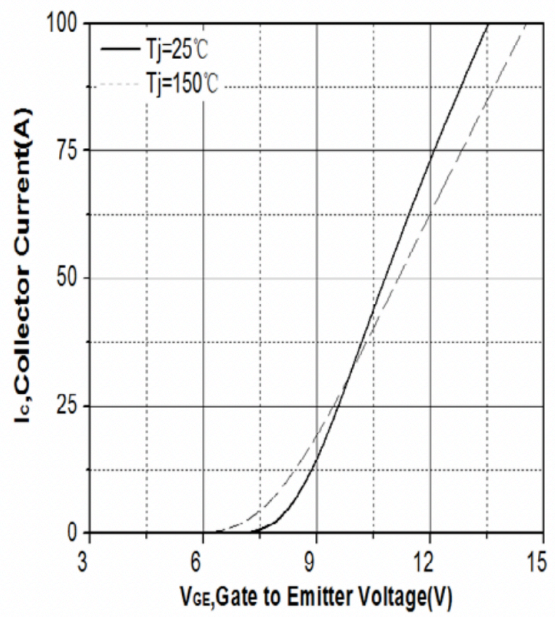


Figure 6. Typical transfer characteristic ( $V_{ce} = 20\text{V}$ )

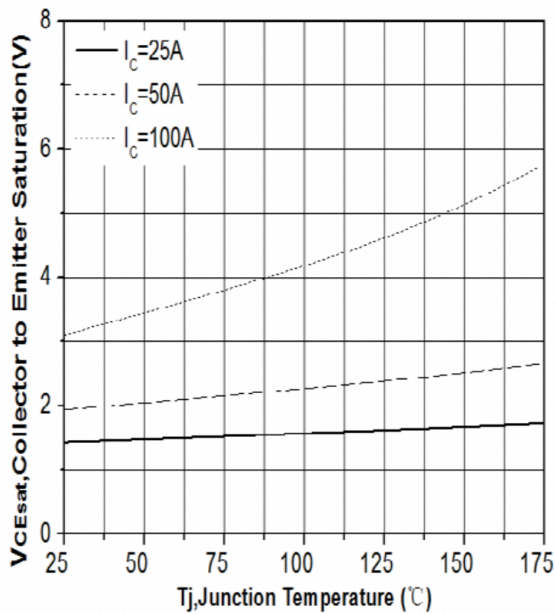


Figure 7. Typical collector-emitter saturation voltage as a function of junction temperature ( $V_{GE} = 15\text{V}$ )

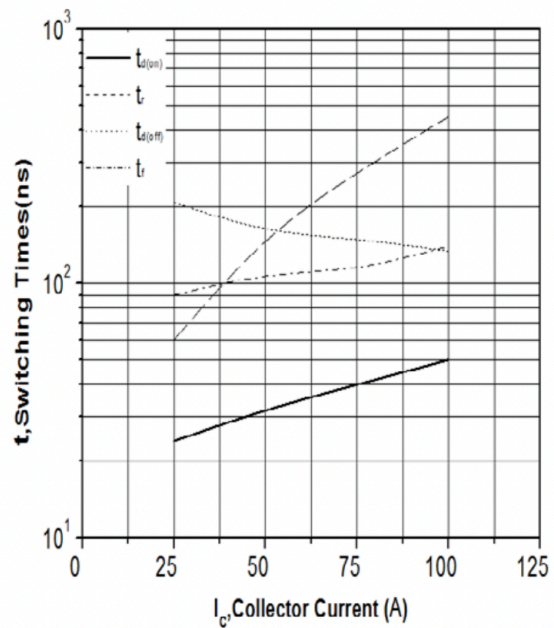


Figure 8. Typical switching times as a function of collector current (inductive load,  $T_j = 150^\circ\text{C}$ ,  $V_{ce} = 400\text{V}$ ,  $V_{GE} = 0/15\text{V}$ ,  $R_{G(on)} = 12\Omega$ ,  $R_{G(off)} = 12\Omega$ , dynamic test circuit in Figure E)

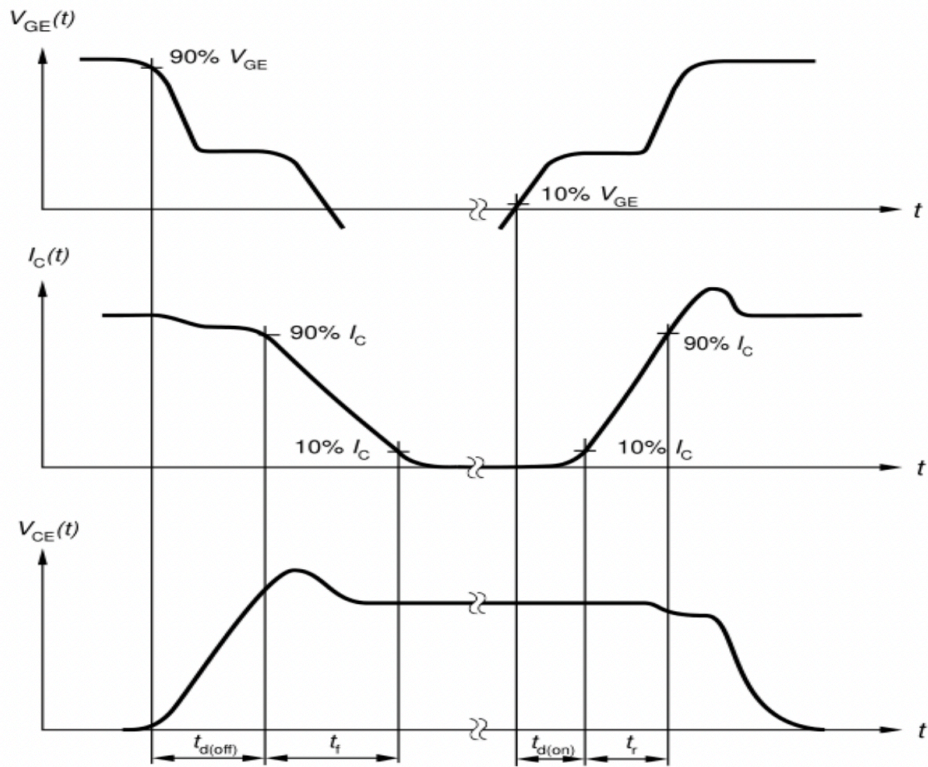


Figure A. Definition of switching times

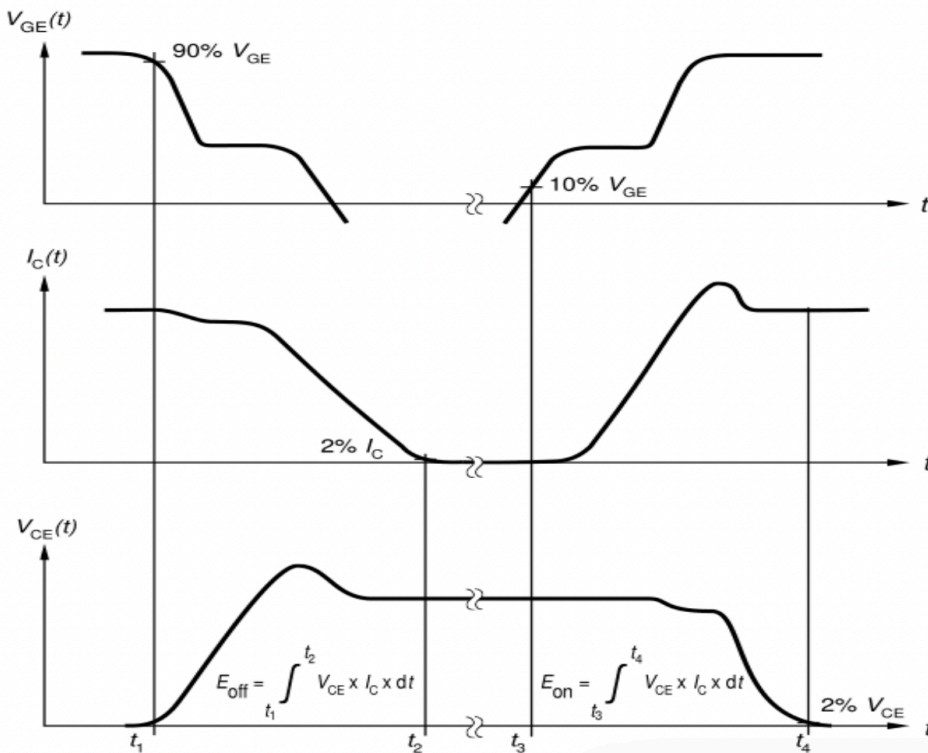


Figure B. Definition of switching losses



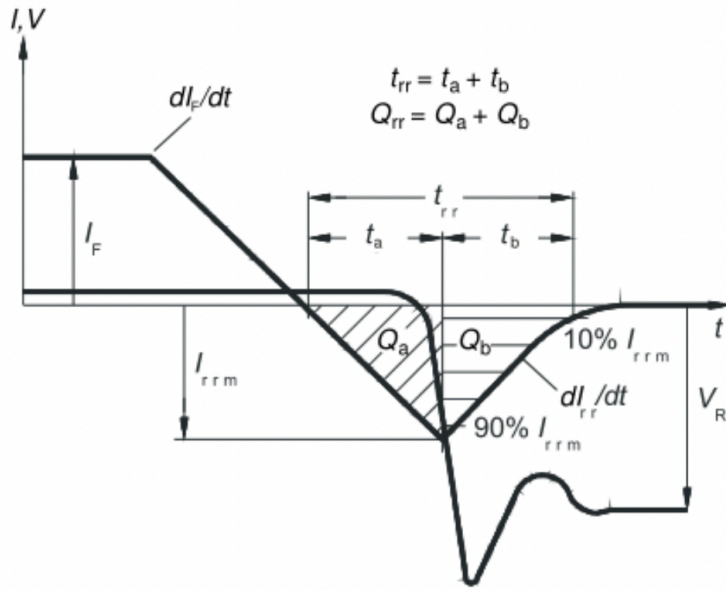


Figure C. Definition of diode switching characteristics

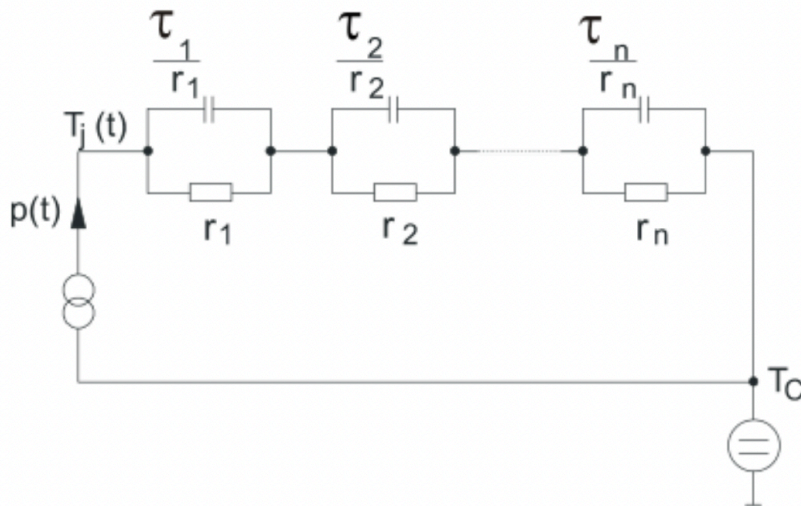


Figure D. Thermal equivalent circuit

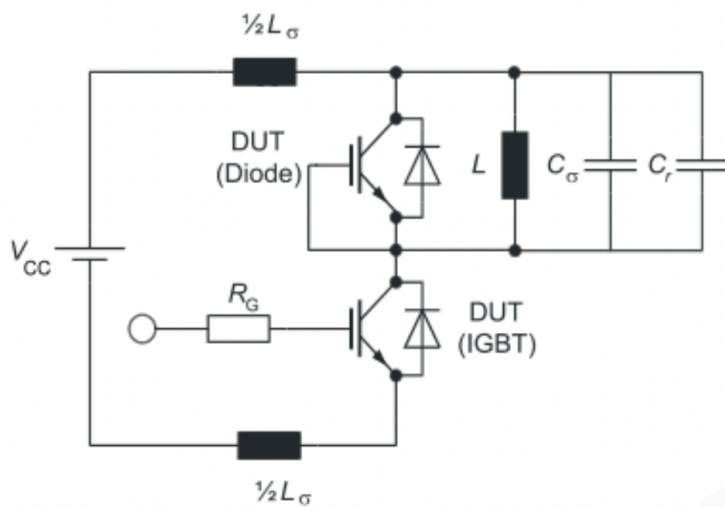


Figure E. Dynamic test circuit  
Parasitic inductance  $L_\sigma$ ,  
parasitic capacitor  $C_\sigma$ ,  
relief capacitor  $C_r$ ,  
(only for ZVT switching)